

## Notice of References Cited

Application/Control No.	Applicant(s)/Pate	nt Under
09/788,335	Reexamination JAFFRAY ET AL.	
Examiner	Art Unit	
Allen C. Ho	2882	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,385,288 B1	05-2002	Kanematsu	378/65
	В	US-6,385,286 B1	05-2002	Fitchard et al.	378/65
	С	US-6,318,892 B1	11-2001	Suzuki et al.	378/197
	D	US-6,148,058	11-2000	Dobbs	378/19
	E	US-6,041,097	03-2000	Roos et al.	378/62
	F	US-5,848,126	12-1998	Fujita et al.	378/195
	G	US-5,675,625	10-1997	Röckseisen	378/206
	Н	US-4,547,892	10-1985	Richey et al.	378/8
	ı	US-			
	J	US-			
	к	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					,
	Ρ	•••				
	ď					
	R					
	Ø					
	۲					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	B. D. Cullity. Elements of X-Ray Diffraction, Second Edition (Reading, MA: Addison-Wesley, 1978), p. 6-12.
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.